





# BRIGHT LED ELECTRONICS CORP.

□□□□R□□□□TR□□□A□□ AEC-Q102 Qualified

## ● Electrical Parameters at 25°C

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Operating Voltage	V <sub>OP</sub>					V
Input Voltage (V <sub>IL</sub> )	V <sub>IL</sub>	Diode Reverse				V
	V <sub>IL</sub>	Diode Forward			0.0V	V
Static Current	I <sub>DD</sub>	V <sub>DD</sub> = 0V, I <sub>out</sub> = "0"				mA
Resistor Current	I <sub>out</sub>					mA
Frequency (f <sub>o</sub> )	f <sub>o</sub>					MHz
Frequency (f <sub>M</sub> )	f <sub>M</sub>					MHz
Turn-on Time (t <sub>on</sub> )	t <sub>on</sub>					ns
Turn-off Time (t <sub>off</sub> )	t <sub>off</sub>					ns
Delay Time (t <sub>d</sub> )	t <sub>d</sub>					ns
Propagation Delay (t <sub>pd</sub> )	t <sub>pd</sub>					ns

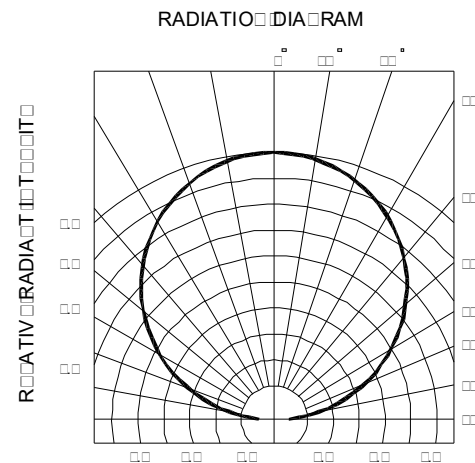
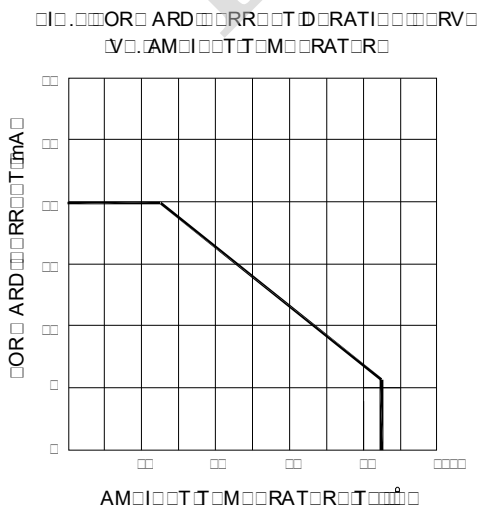
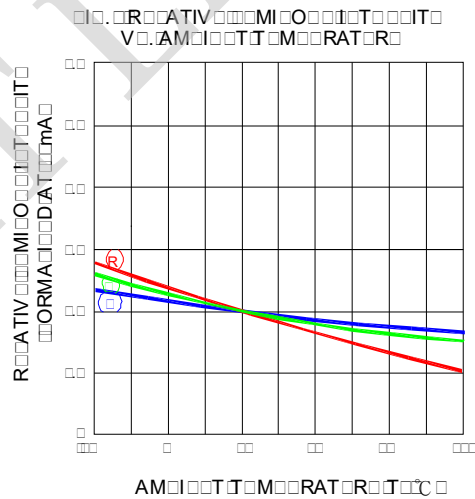
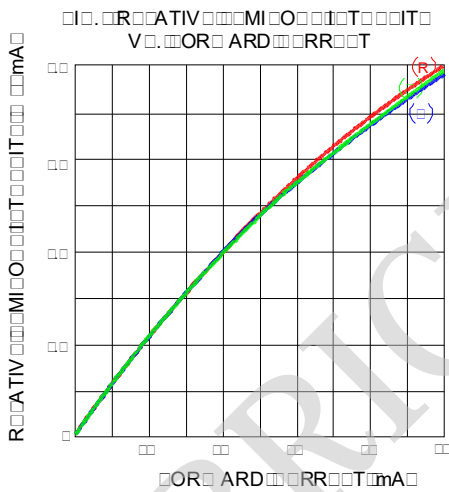
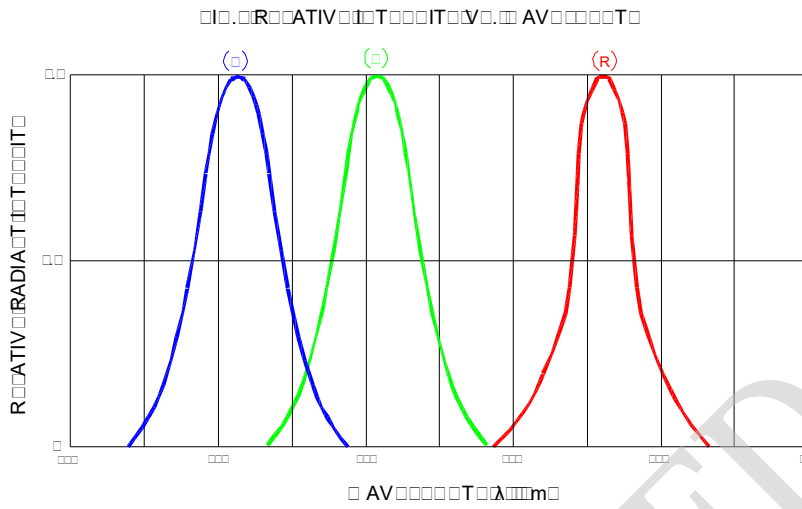
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## ● Optical Parameters at 25°C

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Luminous Intensity (I <sub>v</sub> )	I <sub>v</sub> (R)	I <sub>out</sub> = 10mA				md
	I <sub>v</sub> (F)	I <sub>out</sub> = 10mA				md
	I <sub>v</sub> (B)	I <sub>out</sub> = 10mA				md
Dominant Wavelength (λ <sub>d</sub> )	λ <sub>d</sub> (R)	I <sub>out</sub> = 10mA				nm
	λ <sub>d</sub> (F)	I <sub>out</sub> = 10mA				nm
	λ <sub>d</sub> (B)	I <sub>out</sub> = 10mA				nm
View Angle (θ)	θ	I <sub>out</sub> = 10mA				deg

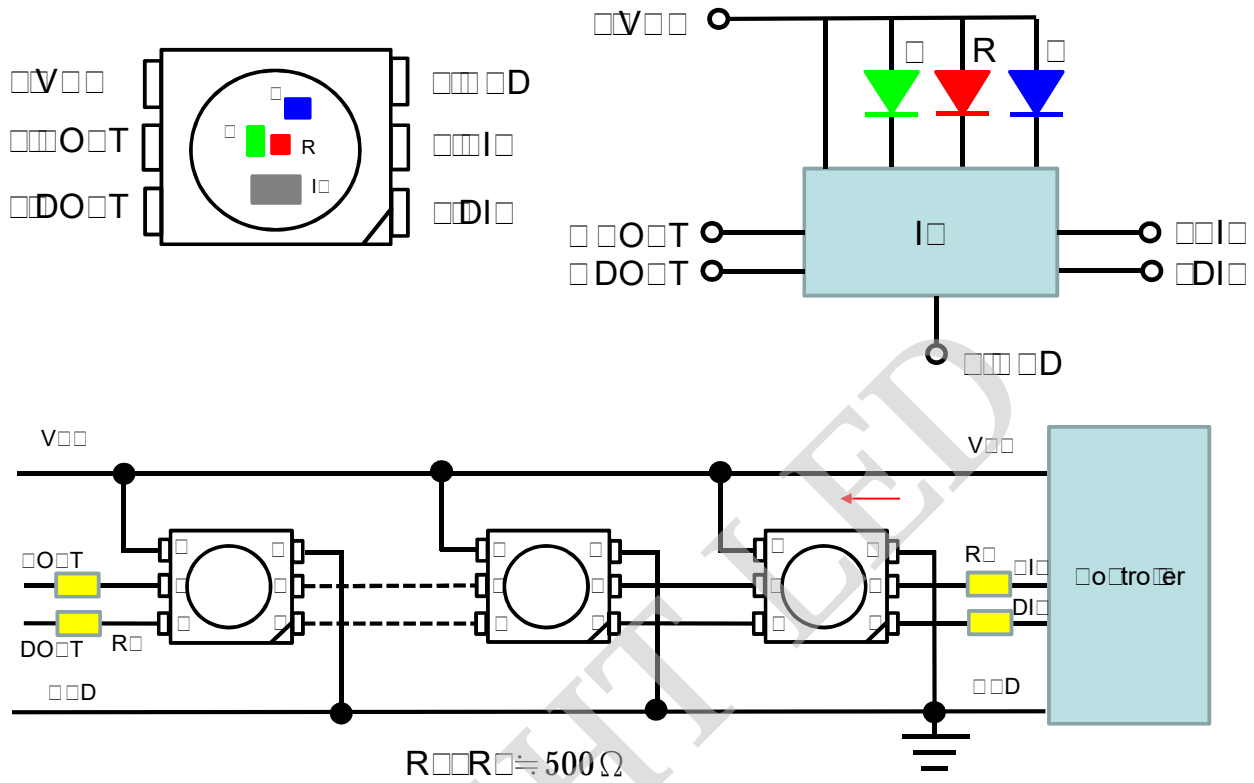


## Electrical Characteristics Curves

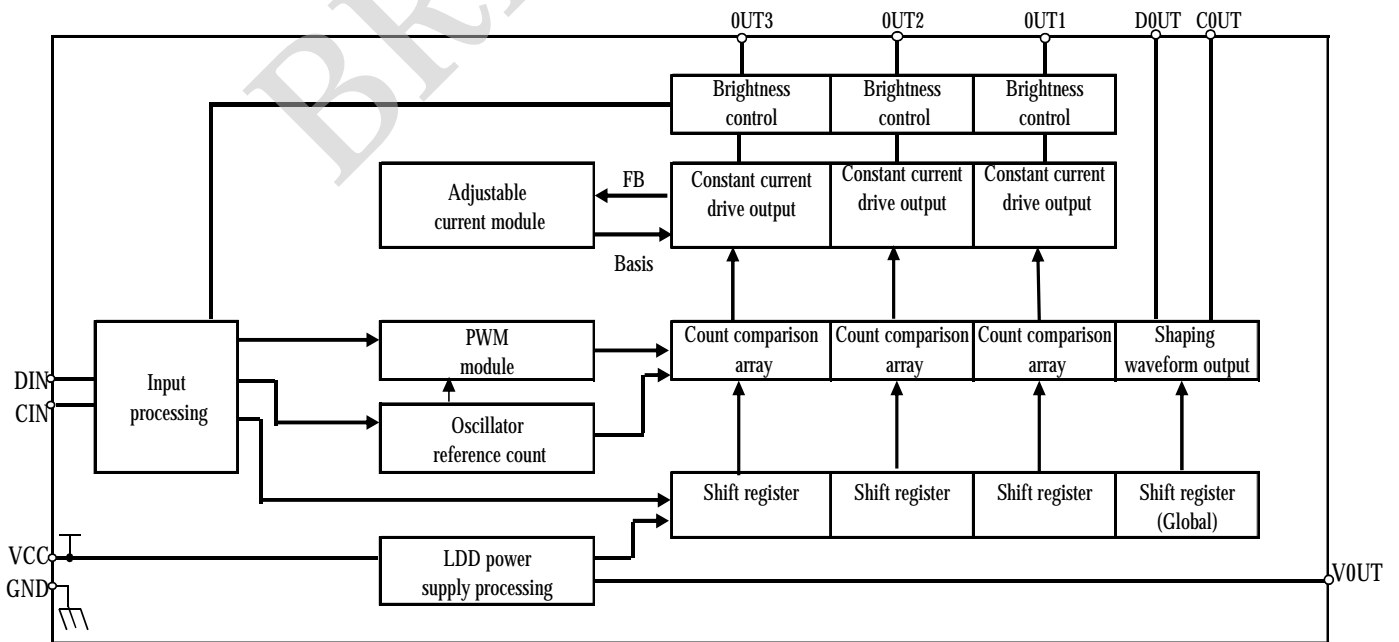




● Circuit diagram

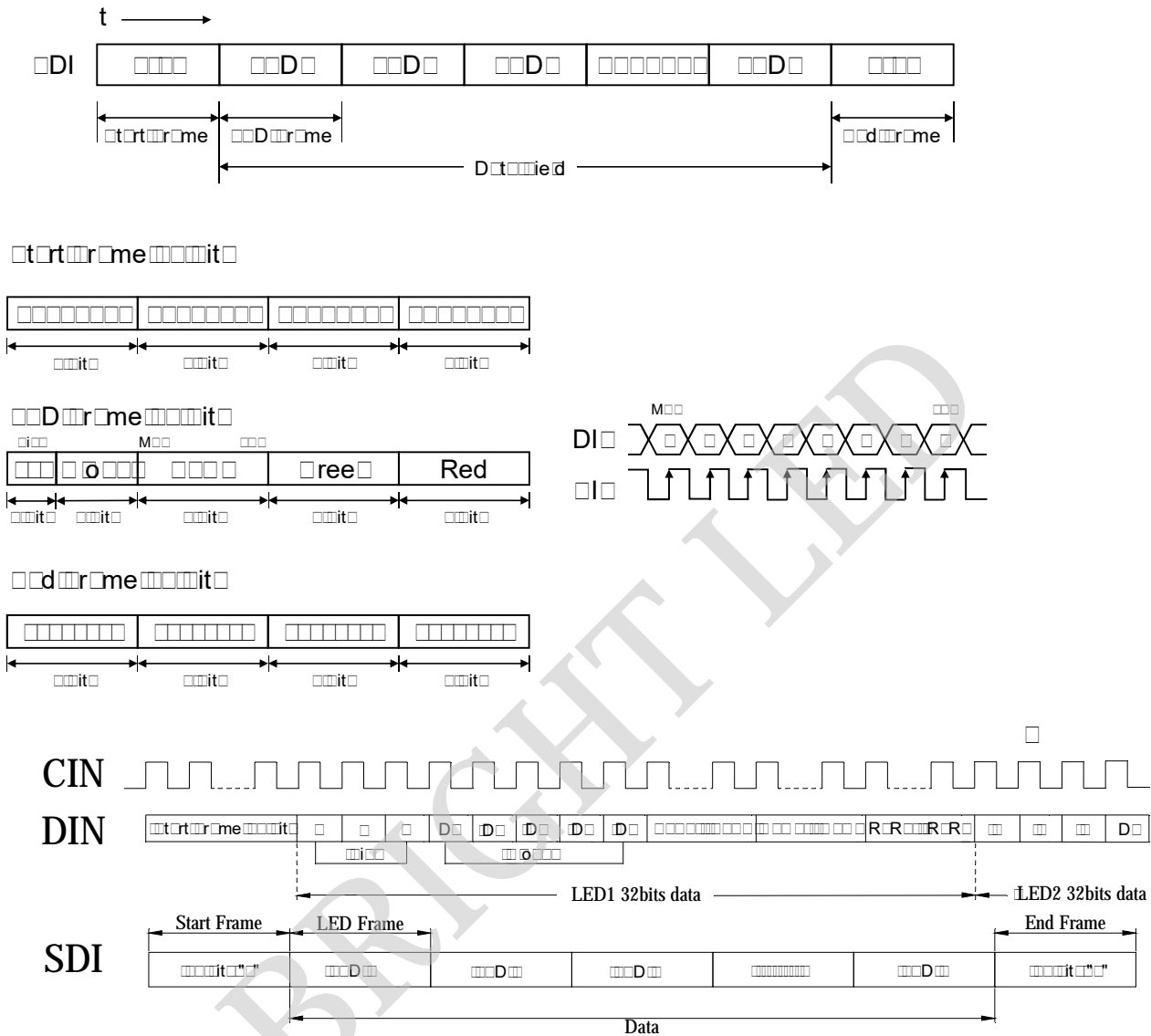


● IC functional block diagram





● **LED Data Frame**



● **Local Data Register Address**

DATA M <sub>0</sub> ← → L <sub>0</sub>	Driver Current
0000	0.1 mA
0001	1 mA
0010	2 mA
...	...
1110	0.1 A
1111	1.1 A

● **Register Data Register Address**

DATA M <sub>0</sub> ← → L <sub>0</sub>	Data Code
0000000	0.2 mA
0000001	1.2 mA
0000010	2.2 mA
...	...
1111110	2.2 A
1111111	2.2 A





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ROHS TR A AEC-Q102 Qualified

## Reliability Test

Classification	Condition	Reference Standard	Condition	Result
Durability Test	Operation	MIL-STD-883C	V <sub>out</sub> mA Temperature Time	
	Temperature	MIL-STD-883C	Temp ± °C Rate Time	
	Temperature Humidity Shock	MIL-STD-883C	Temp ± °C Time	
	Temperature Shock	MIL-STD-883C	Temp ± °C Time	
Environment Test	Temperature Shock	MIL-STD-883C MIL-STD-883C MIL-STD-883C A	Temp mi mi mi mi Time	
	Temperature Shock	MIL-STD-883C MIL-STD-883C MIL-STD-883C	Temp ± °C mi mi Time	
	Order Retention	MIL-STD-883C MIL-STD-883C A	Retention : Temp Operation : Temp M	

## Failure Criteria for Reliability

Measurement	Unit	Measurement Condition	Failure Criteria
Output	mA	V <sub>out</sub> mA	

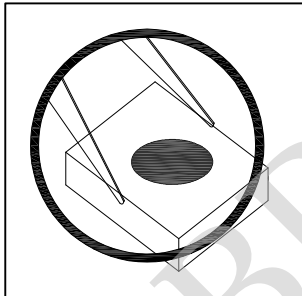
Note: The test limit is defined by the characteristics of the device.

After the test, the test piece is returned to the manufacturer for the temperature test time measurement.

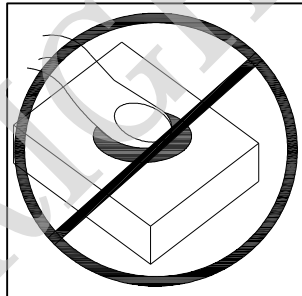




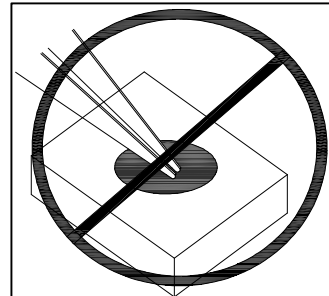
- **Handling Precautions**
- From reference to the user manual, it is recommended to write the following to the user manual.
  - At the time of the test, it is recommended to reduce the test temperature to more than 10°C to avoid the test error.
  - A reference to the test results should be observed during the test.
  - It is recommended to use the test results to determine the test results.
  - Do not direct the user or the test results to the user. It is recommended to use the test results.
  - Do not use the test results to determine the test results.
  - The outer diameter of the MD is recommended to be used to determine the test results.
  - A minimum diameter of the MD is recommended to be used to determine the test results.
  - The diameter of the MD is recommended to be used to determine the test results.



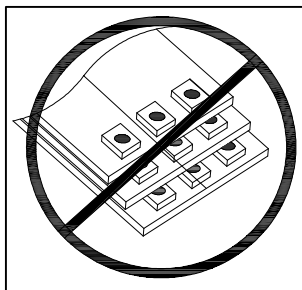
**Pic.1**



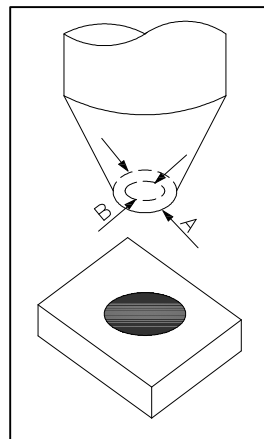
**Pic.2**



**Pic.3**



**Pic.4**



**Pic.5**

